

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination DERDERIAN ET AL.	
		Examiner Julio J. Maldonado	Art Unit 2823	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,410,185	04-1995	Yeh, Jenn L.	257/776
	B	US-5,489,548	02-1996	Nishioka et al.	438/396
	C	US-5,506,166	04-1996	Sandhu et al.	438/396
	D	US-5,580,615	12-1996	Itoh et al.	438/676
	E	US-5,641,991	06-1997	Sakoh, Takashi	257/755
	F	US-5,699,291	12-1997	Tsunemine, Yoshikazu	365/149
	G	US-6,071,770	06-2000	Roh, Jae Sung	438/240
	H	US-6,180,970 B1	01-2001	Hwang et al.	257/295
	I	US-6,090,697	07-2000	Xing et al.	438/618
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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